

Notice of References Cited	Application/Control No. 10/573,116		Applicant(s)/Patent Under Reexamination HUHSE ET AL.	
	Examiner SAMUEL A. TURNER		Art Unit 2877	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,293,213	03-1994	Klein et al.	356/484
*	C	US-5,748,309	05-1998	van der Weide et al.	356/326
*	D	US-6,160,626	12-2000	Debeau et al.	356/451
*	E	US-7,239,396	07-2007	Krause et al.	356/477
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NON-PATENT DOCUMENTS

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	U	Kawanishi et al, A Very Wide-Band Frequency Response Measurement System Using Optical Heterodyne Detection, IEEE Transactions on Instrumentation and Measurement, Vol. 38, No. 2, 4/1989, pp. 569-573.
	V	Kawanishi et al, Wide-Band Frequency-Response Measurement of Optical Receivers Using Optical Heterodyne Detection, Journal of Lightwave Technology, Vol. 7, No. 1, 1/1989, pp. 92-98.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.